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11 TITLE (Include Security Classification) Corrosion Measurements usi	ng Microelectrø	des		•		
12 PERSONAL AUTHOR(S) Kazimierz Wikiel and Janet	Ostervoura					
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OFFICE OF NAVAL RESEARCH

Contract N00014-84-K-0052

Task No. NR 051-855

TECHNICAL REPORT NO. 19

Corrosion Measurements using Microelectrodes

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Kazimierz Wikiel and Janet Osteryoung

Published in

Journal of Electrochemical Society

State University of New York at Buffalo
Department of Chemistry
Buffalo, New York 14214

July 1988

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Corrosion Measurements Using Microelectrodes

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It is shown that microelectrodes can be substituted for large area electrodes in typical corrosion measurements. Results obtained for copper and iron in concentrated solutions are consistent with earlier literature reports. Application of microelectrodes markedly reduces effects of IR-ohmic drops. It allows one to apply electrochemical methods in corrosion investigations under conditions closer to those of natural corrosion environments. The corrosion rate of circular copper microelectrodes in 0.1 mol dm $^{-3}$ HCl solution depends on radius and increases with decreasing radius.



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INTRODUCTION

Unique features of very small, micrometer-size voltammetric electrodes cause the range of their application to be extended continously.

Microelectrodes have been used to solve neurophysiological problems both in vivo and in vitro [1-6]. Arrays of carbon fibers have been used as a voltammetric detector in high-performance liquid chromatography [7], whereas single ultramicroelectrodes have been applied in fast spectroelectrochemistry [8-10]. Microelectrodes have been used in electrochemical investigations in solvent without background electrolyte in order to reduce the effects of ohmic potential drops [11-16] or to extend the accessible potential range [17,18]. Microelectrodes have made it possible to make electrochemical measurements in such novel media as glass solvent eutectics [19] and the gas phase [20]. Micrometer size electrodes have been used in kinetics studies [21-23] and in investigations of nucleation of mercury at a microelectrode surface [22].

In this report we show that microelectrodes can be substituted for large area electrodes in typical corrosion measurements, and that the application of such small electrodes can give some novel advantages. The main advantage is that very high current densities can be achieved at low currents. Thus ohmic polarization can be made negligible even when the specific conductance of the solution is low. A second advantage is that at small electrodes steady state diffusional profiles are achieved at short times. Thus experiments can be carried out quickly. Finally, the dependence of the response on electrode radius, which is analogous to the dependence on rotation rate for a rotating disk, may prove useful in studies of localized corrosion processes such as pitting.

At an embedded circular electrode of radius r the limiting diffusion-controlled steady-state current for a simple charge transfer process is given by i_s = 4nFDCr, where n is the number of electrons transferred, F the value of the Faraday, and D and C are the diffusion coefficient and bulk concentration, respectively, of reactant.

The steady-state current can be described using a diffusion layer model in which the thickness of the diffusion layer is $\delta = \pi r/4$. In contrast with the corresponding rotating disk case, the diffusion layer thickness does not depend on diffusion coefficient.

Here we describe results for two well-studied processes, the dissolution of iron and copper in deaerated chloride solutions.

EXPERIMENTAL SECTION

Preparation of electrodes. To prepare circular copper electrodes, glass-coated 6 µm (M. Fleischmann) and 10 µm-diameter (Cu-99.99\$, Goodfellow) copper wires were used. A piece of glass-coated wire approximately 3 cm long was sealed in vacuum into a 2-µL glass micropipette (Drumond Scientific Co.) to confer mechanical stability and create a larger diameter insulating plane around the active electrode surface. This was done by inserting the glass-coated wire through the pipet, sealing one end, applying a vacuum, and then sealing a portion of the region under vacuum. The wire was then cut at this inner sealed position. This procedure prevented the copper from reacting chemically during the sealing process. In order to prepare the electrical connection, the inner glass coating from the copper wire was removed by using hydrofluoric acid. Then electrical connection was made with a silver thermosetting preparation (P-310 Johnson

Matthey Ltd.) and after that this part was covered with thermally shrinkable tubing. The cross section of copper sealed in glass was polished carefully by using a rotating wheel covered with a Carbimet paper disk with decreasing grit size and subsequently with Microcloth polishing cloth with 1.0, 0.3 and 0.05-µm alumina suspensions (Buehler Ltd.). The quality of the surface was checked optically with 500x magnification (Leitz-Dievert microscope). Only electrodes without any visible defects on the surface were taken for further experiments. Electrodes were repolished lightly before each experiment.

The preparation of circular iron electrodes (10- μ m diameter, glass coated, 99.99% Fe, Goodfellow) was carried out in a similar way. The initial seal between the glass-coated wire and the capillary was made with epoxy, because it was not possible to seal glass to glass directly in the presence of the reactive iron wire. In this case the inner glass coating was removed in molten sodium hydroxide. The resistance of electrodes was about 30, 10 and 70 Ω for 6- μ m Cu, 10- μ m Cu and 10- μ m Fe, respectively, and less than 1 Ω for electrodes with larger radii.

Instrumentation and chemicals. All experimental control, data collection and calculations were carried out on a DEC PDP 8/e laboratory minicomputer interfaced to an EG&G PARC model 273 potentiostat equipped with a Keithley model 427 current amplifier. The reference electrode was saturated calomel and all potentials are quoted with respect to this. A platinum counter electrode was used.

All reagents were of analytical grade, and distilled water passed through a Millipore Milli-Q purification system was used for preparation of the solutions. Solutions were purged with purified argon for at least 20 min. before each experiment. After purging, the argon was directed over the solution.

After a step-wise change in potential the steady-state value of current at an embedded circular electrode is achieved within 5% by time(s) $6 \times 10^6 r^2$, where r is in cm (assuming D = $9 \times 10^{-6} \text{ cm}^2/\text{s}$). In this work electrodes of r=3, 5, 12.5, and 63.5×10^{-4} cm were used. The corresponding times are 0.5, 1.4, 8.9, and 242 s, respectively. Experiments described here were carried out employing a staircase potential-time waveform with 2 mV step height and 2 s period. Thus all the data at the 6 and 10 μ m-diameter electrodes are obtained under diffusional steady state conditions, whereas for the 25- μ m electrode the first few points should exceed the steady state values. The very long times required to achieve steady-state diffusion at the 127- μ m electrode produce a different situation in which relaxation of concentration gradients is promoted by natural convection.

RESULTS AND DISCUSSION

Typical anodic and cathodic polarization curves for a 25-µm diameter copper electrode in deoxygenated 0.1 mol dm⁻³ HCl solution are shown in Fig. 1. The cathodic Tafel plot has a slope of 120 mV/decade which is close to the values reported in the literature [24,25]. The anodic polarization curve consists of two regions and also agrees well with previous reports [25-30]. The first part is a straight line with slope about 60 mV/decade. The second part, occuring at potentials more positive than 0.0 V, has a higher slope. These two regions are separated by a region which displays some oscillations in the current.

The first part corresponds to the diffusion-controlled dissolution of CuCl_2^- as a final product, according to the overall equation:

$$Cu + 2 C1^{-} + CuC1_{2}^{-} + e^{-}$$
 (1)

According to Moreau [29,30] this reaction consists of three successive steps:

$$Cu + Cl^{-} \stackrel{\updownarrow}{\leftarrow} CuCl_{ads} + e^{-}$$
 (2)

$$CuC1 + C1^{-} \stackrel{?}{\leftarrow} CuC1_{2}^{-} \tag{4}$$

In this potential region the rate is governed entirely by diffusion on a uniform reaction surface. Braun and Nobe [28] have shown that diffusion of the chloride ions to the electrode surface is the rate-determining step under these conditions. For reaction (1) the Nernstian relation is

$$E = E_{1/2} - (1/f) \ln\{2(1-i/i_d)^2/(i/i_d)\}$$

$$E_{1/2} = E^{\circ}_{Cu^+/Cu} - (1/f) \ln\{\beta_2^{D}_{CuCl_2}^{C}_{Cl_2}^{C}_{Cl_2}^{C}\}$$
(5)

where $i_d = {}^4FD_{Cl}{}^C{}_{Cl}{}^r$, f = F/RT, and β_2 is the overall formation constant for $CuCl_2^-$. For small values of i/i_d the quantity $(1-i/i_d)^2$ may be approximated by unity. In fact the limiting current is not accessible experimentally, so in practice eq. (5) can only be applied when i/i_d is small. Rearranging we obtain

$$i = 4FD_{CuCl_2}C_{Cl_2}^2\beta_2 r \exp\{f(E-E^{\circ})\}\$$
 (6)

Expressing this relation in terms of current density and steady-state diffusion layer thickness, $\delta_{\rm s}$, we obtain

$$1/A = (FD_{CuCl_2}C_{Cl}^2\beta_2/\delta_g)exp\{f(E-E^\circ)\}$$

$$Cu^+/Cu$$
(7)

This expression is equivalent to that derived from the kinetic viewpoint by Smyrl [25]. In Figure 1, the maximum value of i/i_d is about 0.2, so eqn.

(7) is a reasonable approximation which predicts the observed slope alogitate = 60 mV. We will return below to the question of dependence on concentration of chloride.

The steady-state voltammogram of Figure 2 shows more clearly the region of current oscillation. The details of the response here vary from experiment to experiment, but the general features are reproducible. Returning to Figure 1, the second part of the anodic copper dissolution curve, occurring beyond the region of current oscillations at more positive potentials, corresponds to transpassive dissolution of copper. Moreau [30], using X-ray diffraction methods, has identified two solid products at the copper surface, CuCl and Cu₂(OH)₃Cl. Also Cooper and Bartlett [31] have observed formation of Cu(II) during anodic dissolution in this potential region. Up to 30% of the anodic current was attributed to formation of Cu(II). Overshoots and oscillations at the beginning of this region (cf. Figure 2) were attributed to the formation and dissolution of a multilayer film on the electrode surface [31].

From the above it follows that results obtained at the circular copper microelectrode are in good agreement with the earlier data in the literature. Thus electrodes of small size are certainly appropriate for corrosion measurements. The small size also permits rapid measurements in the steady-state diffusional regime and thus reduces the amount of change in the surface during the course of the measurement. In the present case (Figure 1) with an effective potential scan rate of 1 m V/s, the amount of material lost in scanning from the corrosion potential to the passivation potential corresponds to about 0.3 µm thickness of copper. Halving the scan rate would double that thickness.

The most important feature of the microelectrode is that the same valuable data available from large electrodes can be obtained by measuring very small total currents. At microelectrodes small currents give rise to relatively high current densities. This is shown in Figure 3, which

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presents a Tafel plot for anodic dissolution of a smaller (10-µm diameter) circular iron electrode in 1 mol dm⁻³ potassium chloride solution. Usually, even at such high concentrations of supporting electrolyte, anomalies in current-potential plots are observed very easily when conventional-size electrodes are used. These deviations are caused by ohmic iR-drops in the region of higher current densities, even if a Luggin probe is employed. In order to obtain plots of the proper shape, such techniques as positive feedback, current interruption, or some methods of calculations have to be used. This is unnecessary when microelectrodes with very small surface area are used instead of a conventional size electrode. For the microelectrode (Figure 3) a straight line log plot for anodic iron dissolution without any evidence of iR ohmic drops is observed up to 0.2 A/cm², i.e. to the region where some effects connected to the transpassive dissolution of iron have been observed. Moreover a Luggin probe was not used in these experiments.

The anodic Tafel slope for electrodissolution of iron is about 70 mV/decade, close to the value of 80 mV/decade obtained by Asakura and Nobe [32] for the steady-state anodic polarization of iron in the same unbuffered neutral 1 mol dm $^{-3}$ KCl solution. However, their log plot was obtained by using the current interruption method. The apparent potential-log current relation deviated markedly from linearity for current densities above 10 mA/cm 2 .

Obviously, it is almost impossible to obtain a properly shaped potential-current relation at electrodes of "normal" size in solutions with markedly lower conductivity, even if sophisticated methods of ohmic iR-drop correction would be used. For instance, modern instrumentation such as the PARC 273 potentiostat allows one to compensate ohmic IR drops up to 200 Ω at the 10 mA range or up to 2 M Ω at the 1 μ A range by using positive feedback.

Since the currents at microelectrodes reach the microampere level only in extreme conditions, ohmic iR drops due to high resistance can be corrected as needed. But this iR compensation is inadequate for even routine conditions at a large electrode.

Anodic dissolution curves for iron in 10⁻⁴ mol dm⁻³ KCl solution are shown in Fig. 4. Resistivity of this solution is about 60 kΩ cm⁻¹. Curve A, obtained with a 10 µm-diameter circular electrode, is a straight line up to 10 mA/cm². Small deviations from linearity are observed above this limit. Curve B was obtained with a still small but markedly larger 127-µm diameter iron electrode. No straight line region of the log plot can be identified in this case although the total currents are markedly lower than (less than one-thousandth of) those at electrodes used in typical corrosion measurements. (Note that the maximum current densities are no greater than about 1\$ of those expected for an anodic reaction diffusion-controlled in chloride.)

Since the use of microelectrodes reduces markedly ohmic iR-drops, it allows one to extend the range of corrosion measurements. As an example of such possibilities the anodic dissolution of copper over a wide range of chloride ions concentrations was chosen.

Anodic polarization curves of copper in chloride ion solutions with various concentration are shown in Fig. 5. A circular electrode with diameter of 6 µm was used. Concentrations of chloride ions are in the range 1-10⁻⁴ mol dm⁻³, and no other electrolytes were added to the solutions. Anodic behavior of copper depends markedly on concentration of chloride ion and can be divided into two regions. Above a concentration of 0.01 mol dm⁻³ log plots of anodic dissolution are straight lines and their slopes are approximately 60 mV/decade. According to Smyrl [25] for rotating disk

steady-state currents the anodic dissolution current density in this region can be described by:

$$1/A = (Fk_a D_{CuCl_2} \beta_2 C_{Cl}^2 / k_c \delta_L) exp[(\alpha_a + \alpha_c) f(E-E^\circ)]$$
 (8)

Where $k_{\underline{a}}$ and $\alpha_{\underline{a}}$ are the anodic rate constant and charge transfer coefficient, respectively, and \boldsymbol{k}_{c} and $\boldsymbol{\alpha}_{c}$ are the corresponding cathodic values. The quantity $\boldsymbol{\delta}_L$ is the Levich diffusion-layer thickness. The choice of reference potential makes $k_a = k_c$. Other symbols have their usual meanings. Assuming $\alpha_a = \alpha_c = 0.5$ eq. (8) is equivalent to eq. (5) and the slope of a plot of E vs. log i should be 60 mV/decade. From eq. (8) it follows that current density depends markedly on the concentration of chloride ions. Moreau [29] has investigated the effect of chloride ion concentration on anodic dissolution of copper within the range 0.1 to 10 mol dm^{-3} . He found the value of $(dE/d \log C_{C1})_{1.298} = 118 \text{ mV}$. Our results obtained at copper microelectrodes are in good agreement with the theoretical prediction and with earlier reports. The log plot slopes of 60 mV/decade as well as the shift of the anodic curve 120 mV/decade C_{C1} toward more positive potentials with decreasing chloride concentration down to 0.01 ${\tt mol}\ {\tt dm}^{-3}$ are congruent with literature reports about anodic behavior of copper in solutions with higher chloride concentrations [28-30]. This means that even at chloride concentrations as low as 0.01 mol $\,\mathrm{dm}^{-3}$ the final product of anodic dissolution of copper is CuCl₂, and that diffusion is rate determining. Generally, in this region of chloride concentration the anodic dissolution of copper is governed by diffusion phenomena on a uniformly active surface.

At very low chloride ion concentration changes in shape of the current-potential curve are observed (Fig. 5, curves D.E). The slope of the log plots is 30-40 mV/decade at about 0.1 mA/cm². It should be mentioned that

reproducibility of the results obtained with low chloride concentration is markedly poorer than in the higher range. The smaller slope probably reflects the same phenomenon as in the oscillation region in the solution with higher chloride concentration, i.e. the formation of multilayer films on the electrode surface. The second part of these curves indicate that transpassive oxidation of copper is involved in the electrodissolution process. It would be extraordinarily difficult to correct for iR drops under these conditions because the specific conductance of the solution changes markedly in the vicinity of the electrode during the course of the experiment [33].

Braun and Nobe [28] have estimated that in solution with chloride ion concentration lower than approximately 0.05 mol dm⁻³ a considerable amount of copper is dissolved as non-chloride-complexed copper(II) ions. The thermodynamic potential for equal concentrations of Cu^{2+} and Cu^{+} at the electrode surface is -0.082 V, and CuCl(s) is thermodynamically stable only at more positive potentials. Taking into account only the species Cu^{+} , $CuCl_{2-}$ and Cu^{2+} , the predominant species is $CuCl_{2-}$ except in 10^{-3} and 10^{-4} M Cl_{2-} . For these lower chloride concentrations Cu^{+} predominates except at higher current densities (> 0.6 mA/cm²) where Cu^{2+} becomes increasingly important. Our results confirm the change of electrodissolution mechanism. However, also in the low chloride concentration range $(1\times10^{-3}-1\times10^{-4}$ mol dm⁻³) a considerably smaller but still marked effect of chloride ion concentration on copper electrodissolution is observed.

Equation 5 predicts that the current density for copper dissolution should be inversely proportional to the diffusion layer thickness. The influence of diffusion layer thickness on anodic current density of copper in HCl solutions has been reported [25,28,29]. The thickness of the

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diffusion layer has been changed by changing the rotation rate of a rotating disk electrode. Current densities were observed to increase as the rotation rate was increased. However, Braun and Nobe [28] have not observed direct proportionality to the square root of the rotation rate. Smyrl [25] has reported a closer fit to the expected dependence. Minor deviations have been observed at very high rotation rates. On the other side, Moreau [29] has reported a value of $(dE/d \log_{10} 1/2)_{1,298} = -59$ mV which is in excellent agreement with eq. (5).

Since at microelectrodes the steady-state diffusion layer thickness is proportional to the electrode radius, anodic current density should be inversely proportional to the radius of a circular microelectrode. Typical curves of anodic dissolution of copper microdisk electrodes with different radii in 0.1 mol dm⁻³ hydrochloric acid are presented in Fig. 6. At the same potential value the anodic current density for smaller electrodes is larger than for larger ones. Since the cathodic process of hydrogen evolution does not depend on diffusion phenomena, the corrosion current density and corrosion potential obtained by extrapolation of straight parts of log plots to their intersection depend on the radius of the microelectrode. The corrosion current density is increased and corrosion potential is shifted toward more negative potentials with decrease in microelectrode radius.

An expression for the corrosion current can be obtained by equating the anodic current (eq. (8)) with the negative of the cathodic current (cf. Fig.

$$i_{corr} = k_{cH}^{2/3} (D_{C1} g_2 C_{C1}^{2/\delta})^{1/3}$$
 (9)

where k_{cH} is the rate constant for hydrogen reduction at the corrosion potential. Using the value 1° = $10^{-6.7}$ A/cm² for reduction of H⁺ on Cu

1). Assuming that all transfer coefficients are 0.5, we obtain

[24], $k_{cH} = 10^{-11.7}$ cm/s. A plot of experimental corrosion current density vs $r^{-1/3}$ for electrodes of radii 3, 5, and 12.5 μ m yielded a straight line with correlation coefficient 0.9998 and slope 9.6×10^{-9} A/cm^{5/3}. The slope predicted by eq. (9) with $D_{Cl} = 10^{-5}$ cm²/s is 3.8×10^{-9} A/cm^{5/3}. Considering uncertainties in the data and in the appropriate value of k_{cH} , this is excellent agreement.

The same approach yields the prediction $\partial V_{corr}/\partial \log r = 40$ mV. A plot of E_{corr} vs $\log r$ was linear (correlation coefficient = 0.9996) with slope 26 mV. Thus the shift in corrosion potential is less than predicted.

A final comment on the use of microelectrodes for studying corrosion processes concerns the role of geometry in the formation of single pits.

Beck and Alkire have discussed the role of spherical diffusion in formation of pits [34]. The relation confirmed here between size and corrosion rate for a homogeneous surface demonstrates experimentally the prediction of higher corrosion rates at small sites on a heterogeneous surface.

Furthermore, it seems feasible to study small electrodes under conditions where only one pit can form and thus to examine more quantitatively models which describe this process, especially in its early stages.

ACKNOWLEDGMENTS

This work was supported in part by the Office of Naval Research. The 6-µm diameter copper wires were supplied by Martin Fleischmann, University of Southampton, Southampton, England.

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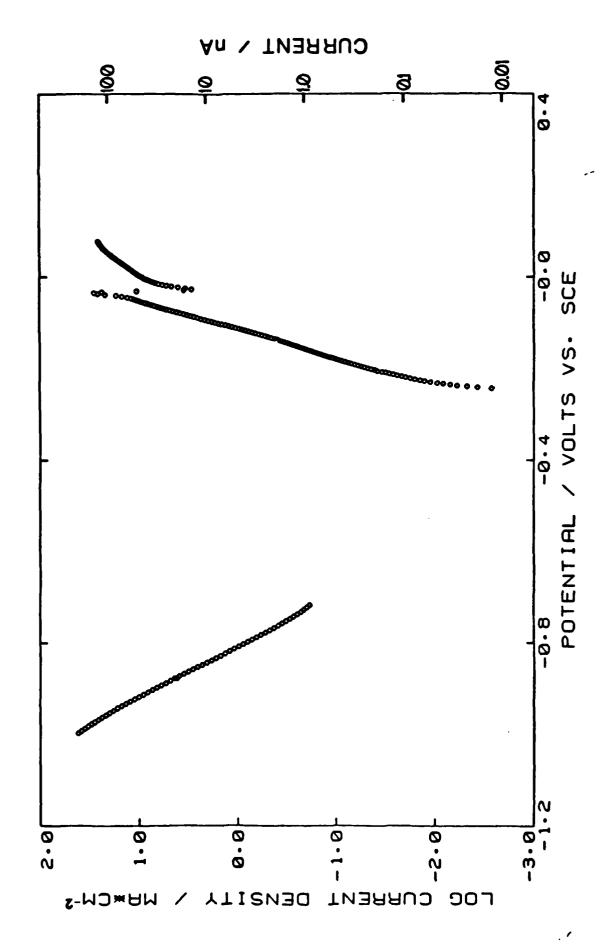
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FIGURE LEGENDS

- Figure 1. Anodic and cathodic polarization of copper in 0.1 mol dm $^{-3}$ HCl solution. Circular copper electrode, diameter 25 μm ; staircase voltammetry: t = 2s; $\Delta E_n = 2mV$.
- Figure 2. Anodic staircase voltammogram of copper in 0.1 mol dm $^{-3}$ HCl. Circular copper electrode, diameter 10 μ m; t = 2s; $\Delta E_{\rm g}$ = 2 mV.
- Figure 3. Anodic polarization of iron in 1 mol dm $^{-3}$ KCl solution. Iron microdisk, 10 μm in diameter. Staircase voltammetry: t = 2s; $\Delta E_{\rm p} = 2mV$.
- Figure 4. Anodic polarization of iron in $1x10^{-4}$ mol dm⁻³ KCl solution. Iron disk: A-10 μ m; B-127 μ m in diameter. Staircase voltammetry: t = 2s; $\Delta E_n = 2mV$.
- Figure 5. Anodic polarization of copper in chloride solutions: 1×10^{-4} mol dm⁻³ HCl +: A- 0.9999; B- 0.0999; C- 0.0099; D- 0.0009; E- 0.0000 mol dm⁻³ KCl. Copper microdisk, 6 μ m in diameter. Staircase voltammetry: t = 2s; $\Delta E_{\rm m} = 2 \, {\rm mV}$.
- Figure 6. Anodic polarization of copper in 0.1 mol dm⁻³ HCl solution. Copper microdisk: A- 6 μm ; B- 25 μm in diameter. Staircase voltammetry: t = 2s; ΔE_{p} = 2 mV.



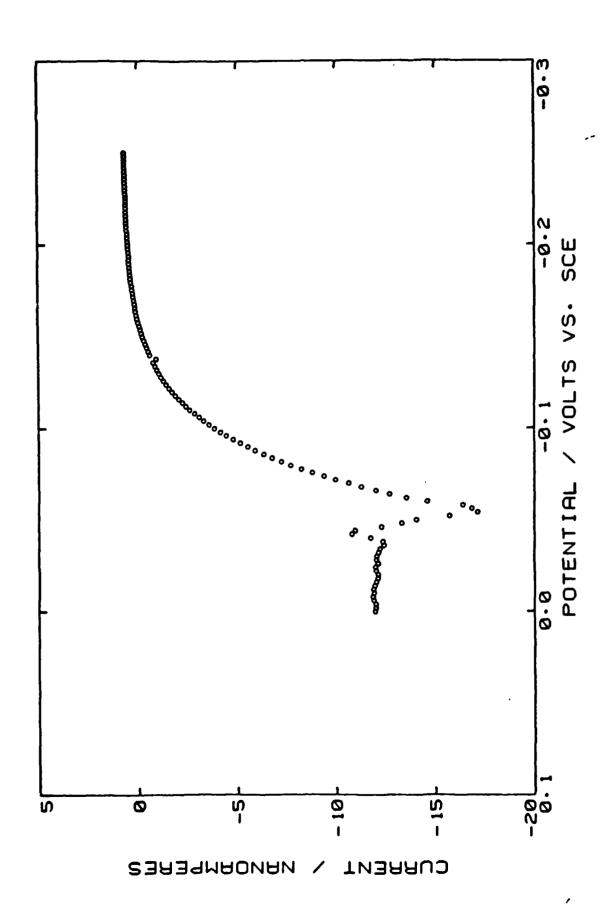


FIGURE 4

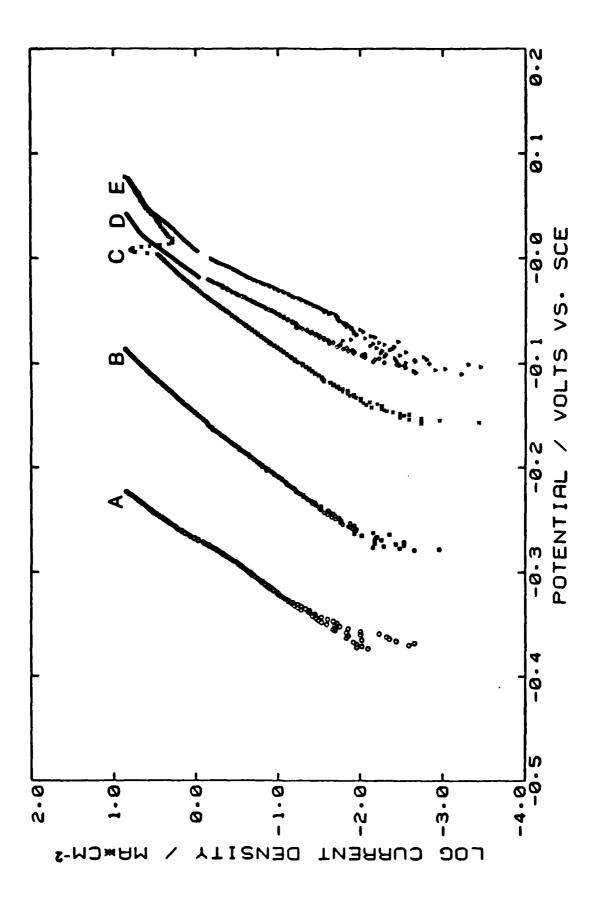
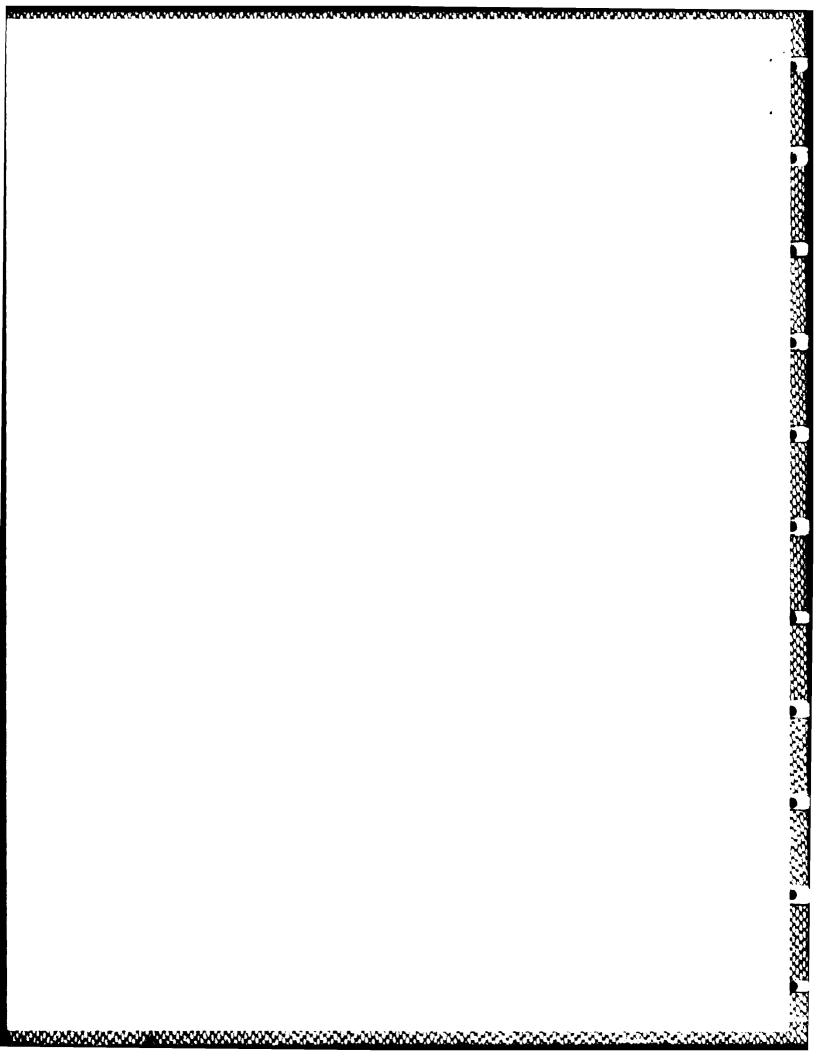


FIGURE 6

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